SM custom electrical device

Beamline: SM

Contact: Jian Wang

A custom-made device for electrical biasing, and total electron yield detection via drain current. Designed to fit the SM standard sample holder.

More information can be found in Zhou, J. Wang et al., PCCP 18, 22789 (2016), and H.W. Nho et al., J. Synchrotron Rad. 21, 170 (2014).